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CUPRINS – CONTENTS

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Pages 2 - 7

The Standard ISO 9001:2015. Changes and Challenges

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Abstract
ISO 9001 is undoubtedly the best known and most widely used of the many standards developed by the International Organization for Standardization (ISO). This paper analyzes – on the basis of documents elaborated by ISO/TC 176 – changes and updates proposed for the new ISO 9001:2015. As one of the key changes in the 2015 revision of ISO 9001 is to establish a systematic approach to risk, a special attention is given to the analysis of the concepts of risk and of risk-based thinking, introduced in this standard. A comparison between the "old standard" ISO 9001:2008 and the "new standard" ISO 9001:2015 is given too.

Keywords: quality, quality management, quality management system, ISO 9001, ISO 9001:2015, standard, International Organization for Standardization ISO, ISO/TC 176, changes, new standard revision, risk, risk-based thinking.

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Asigurarea Calităţii – Quality Assurance, ISSN 1224–5410
Vol. XXI, Issue 81, January-March 2015
Pages 8 - 13

Quality Management in Dental Health Care in the Republic of Serbia

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Abstract
Standards ISO 9000 series, passed in 1987, were the driving force of development and implementation of quality management (QM) in various sectors, including health care. Today there are over one million certificates for QMS, so you could say that they were the main generator of quality improvement. In addition to quality management models of products / services today, in this area, using different models. The aim of this study was to present the methods and techniques to improve the quality of health services, with special emphasis on dental health care services and the aspect of improving quality of it in the Republic of Serbia.

Keywords: quality, health, quality management, health services, dental health care

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Asigurarea Calităţii – Quality Assurance, ISSN 1224–5410
Vol. XXI, Issue 81, January-March 2015
Pages 14 - 21

Detection of Mean Shifts by Statistical Approaches. Part 2: Context of Non-Gaussian or Autocorrelated Observations

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Abstract
This article is the second part of a global overview of the research on the detection of mean shifts through statistical techniques. Various categories of control charts used in the field of Statistical Process Control (SPC) are reviewed in the particular context represented by autocorrelated observations or distributed under non-Gaussian distributions.

Keywords: SPC, APC, control charts, detection, autocorrelated observations, non-Gaussian distributions.

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Vol. XXI, Issue 81, January-March 2015
Pages 22 - 32

High-Power LEDs Lighting Systems Reliability - Understanding of Degradation Processes

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Abstract
With the progress of LED lighting technologies, their application is spreading in sign and display devices, spot lighting, base lighting, and security lighting, and new applications that cannot be realized with conventional light sources are expected. The reliability of LED is key to its application system.

Keywords: degradation mechanisms, failure modes, packaging, phosphors, ESD, EOS, thermal management

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